



Pre-packaging of power components using photosensitive resin

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Pre-packaging of power components using photosensitive resin



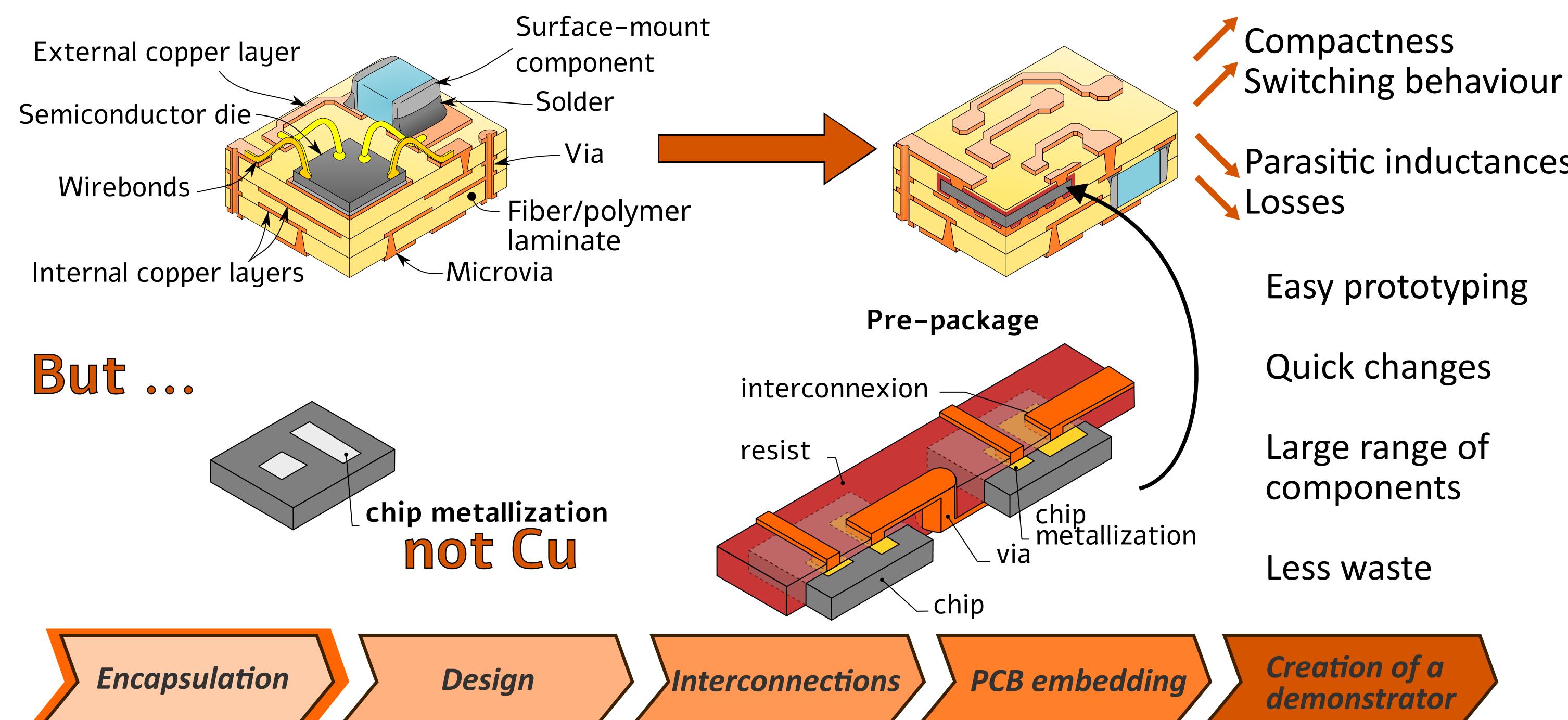
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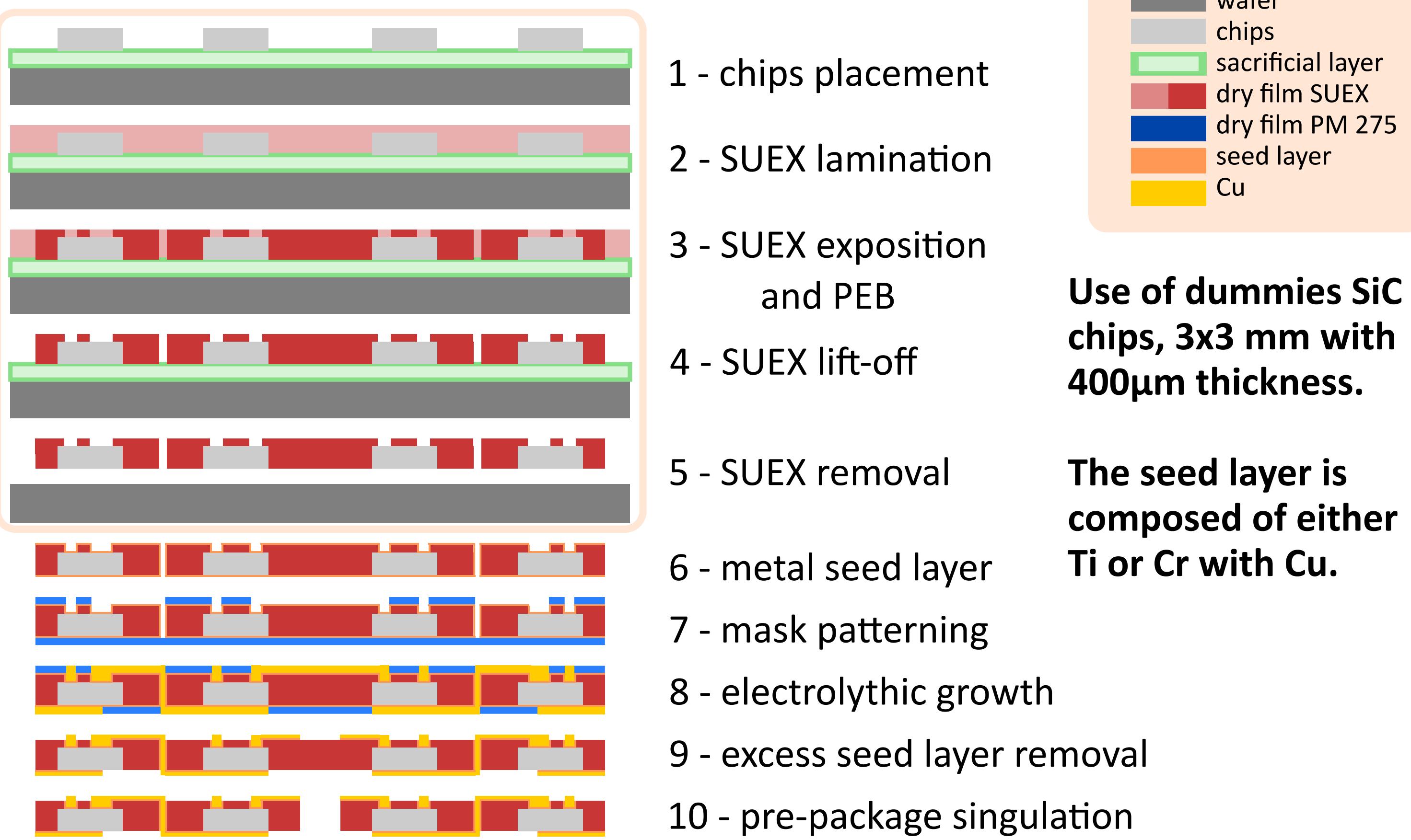


Encapsulation and pre-package

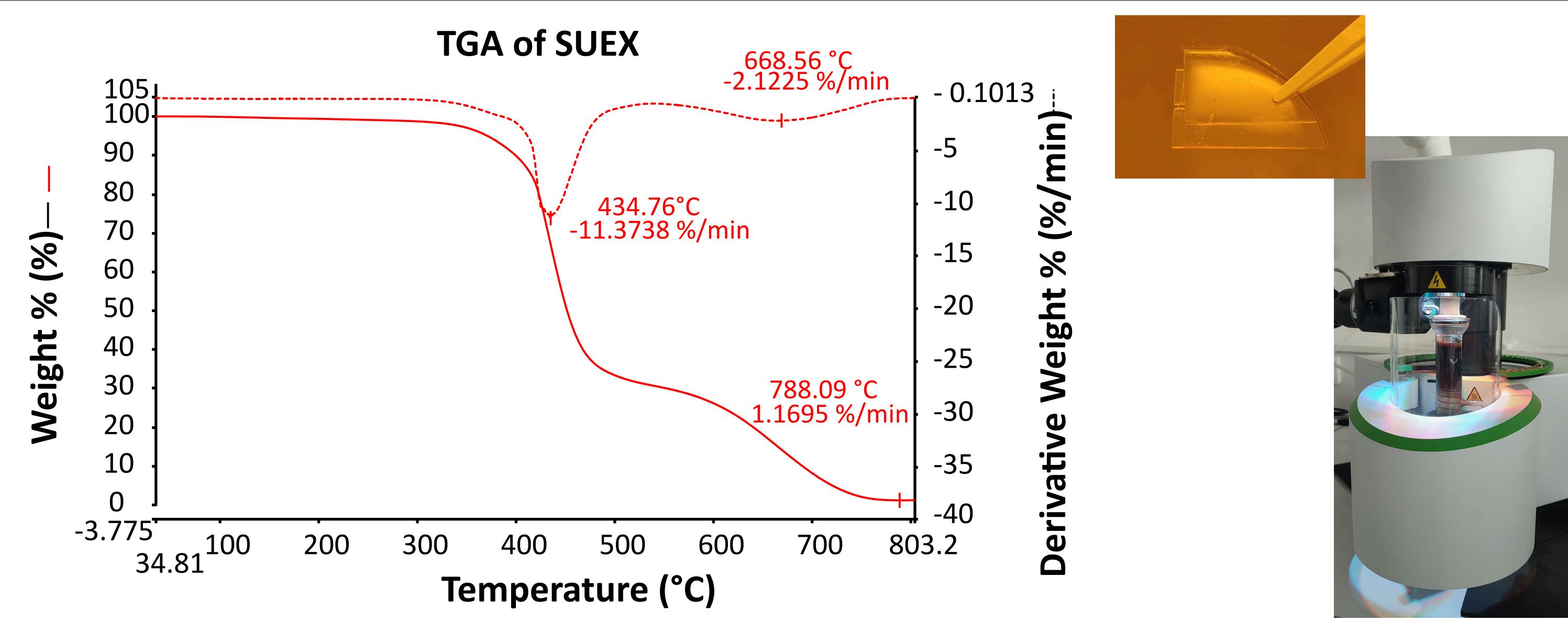


Envisaged process for pre-packages fabrication

SUEX 500µm : dry film negative resin



Material thermal characterization



The TGA (Thermal gravimetric analysis) shows that SUEX start degrading at 434°C, and so is thermally compatible with PCB embedding.

Photos gallery

Sample with best results: 12 - 05 - 65

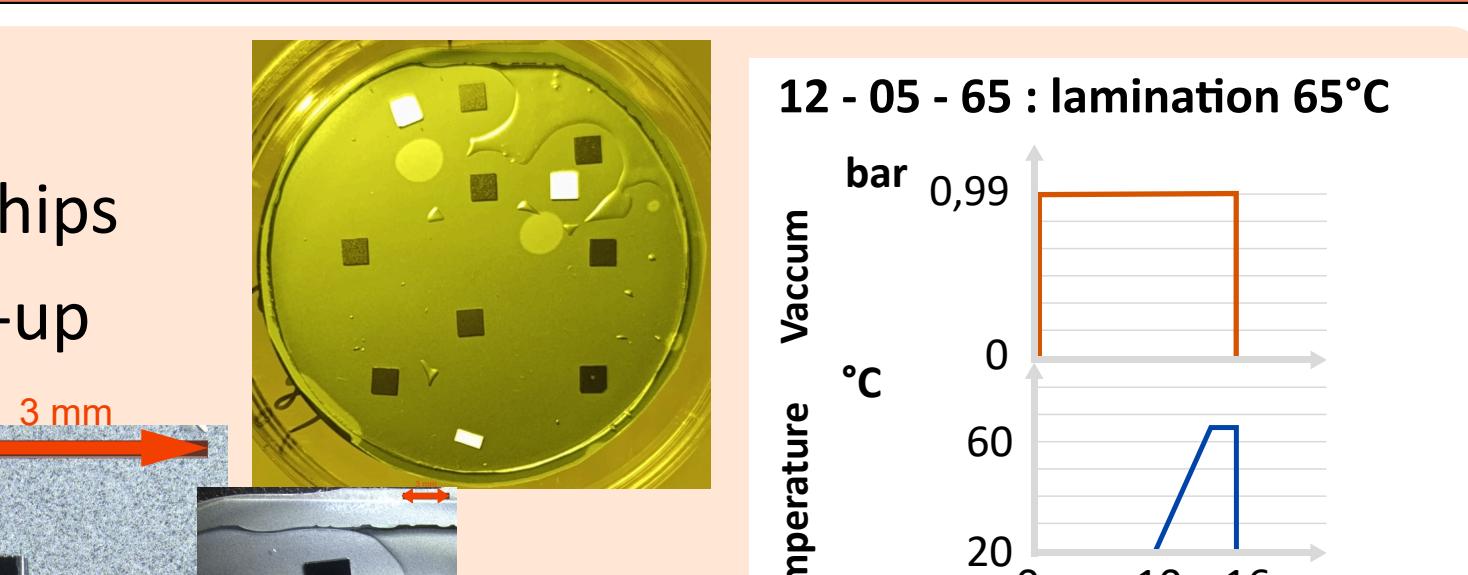
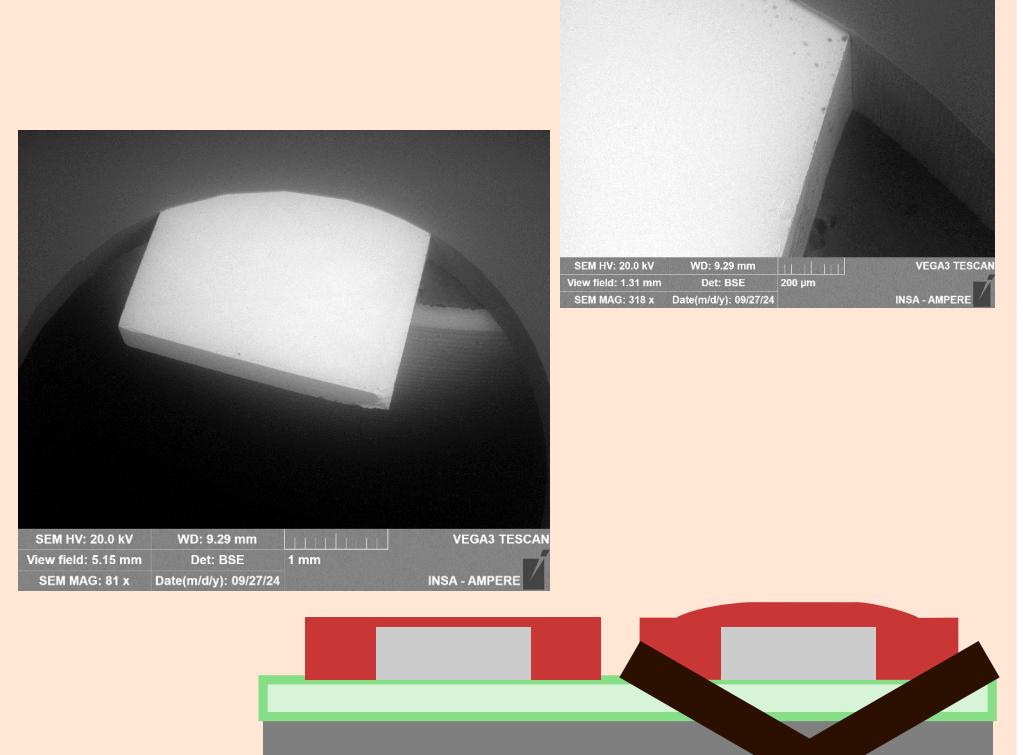
Configuration A, lamination with SUEX on top of chips

Fast heating: lamination at 65°C, with 5 min ramp-up

use of a 1kg mass

under an 0,99 bar vaccum

SEM observations



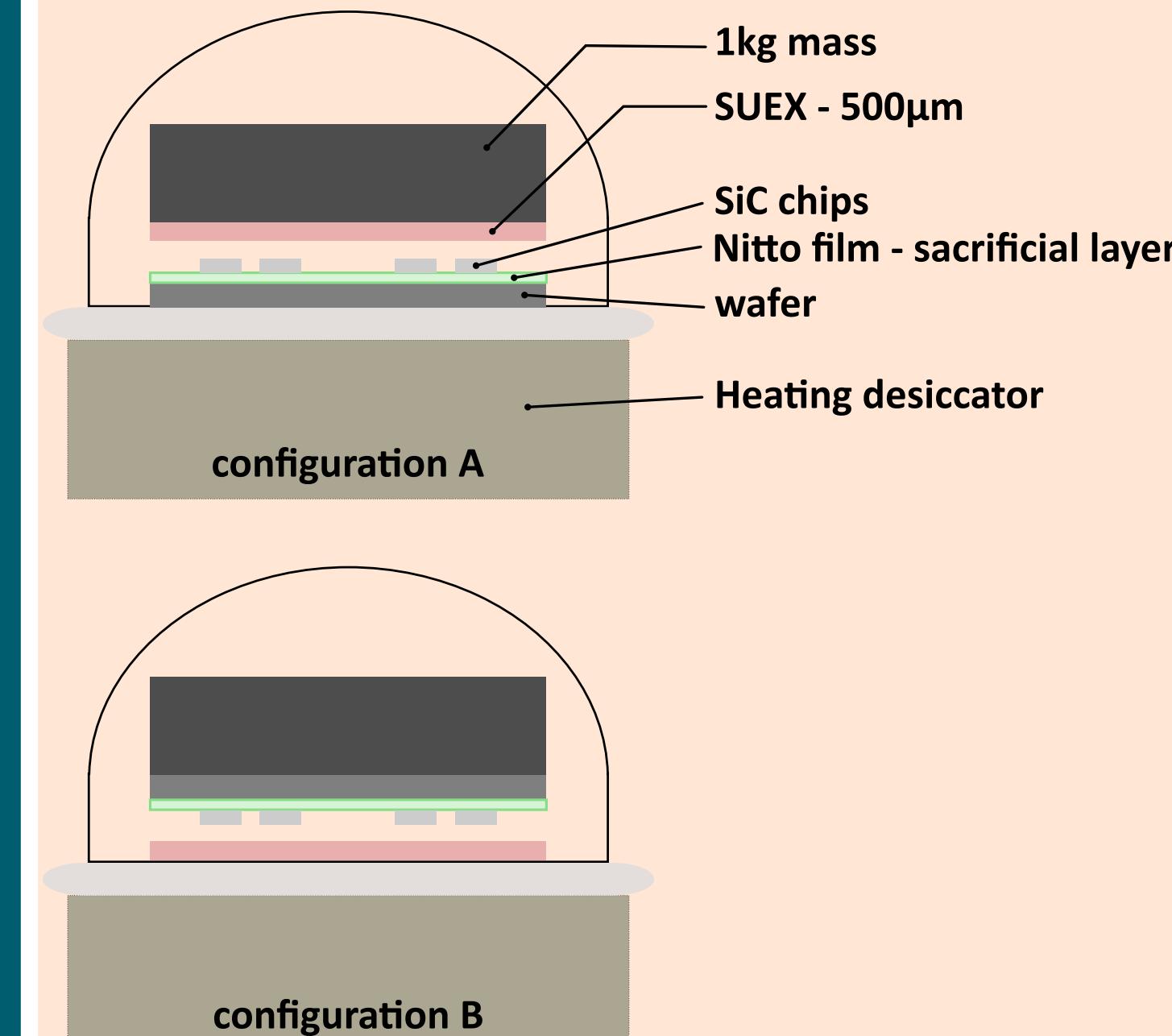
Power component encapsulation specifications

Service function	Assessment criterion	Acceptability level
Encapsulate components	<ul style="list-style-type: none"> Conformal deposition Deposit thickness 	<ul style="list-style-type: none"> Presence of some bubbles tolerated • 500µm
Reduce production costs	<ul style="list-style-type: none"> Simplified tooling Batch process 	• Photolithography techniques
Ensure connectivity with the external environment	<ul style="list-style-type: none"> Access to inferior and superior component's faces Encapsulation opening on the upper surface 	<ul style="list-style-type: none"> Full overlap of component edge • Photosensitive material
Exterior working environment requirements	<ul style="list-style-type: none"> Thermal stability Dielectric strength Pressure 	<ul style="list-style-type: none"> • 150°C fonct / 200°C embedding • Ecrit = 10kV/mm • 2 bar

Encapsulated resin selected: SUEX thick dry films (DJ Laminates)

Methodology

Testing two configurations for SUEX lamination



heating speed: slow (20min ramp-up, 10min soak)
fast (5min ramp-up, 1min soak)

vacuum level: low (-0,6 bars)

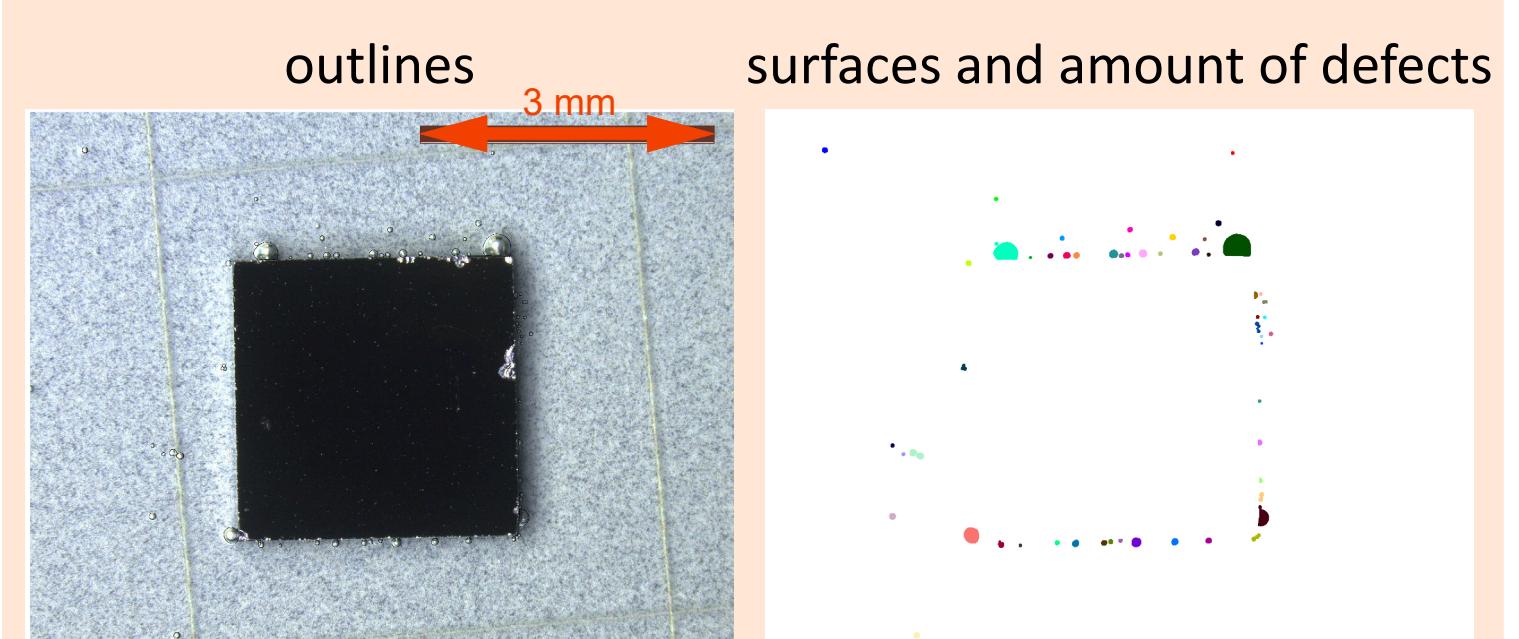
high (-1bar)

drying conditions (temperature, vacuum, duration)

orientation (config A or B)

Parameters investigated

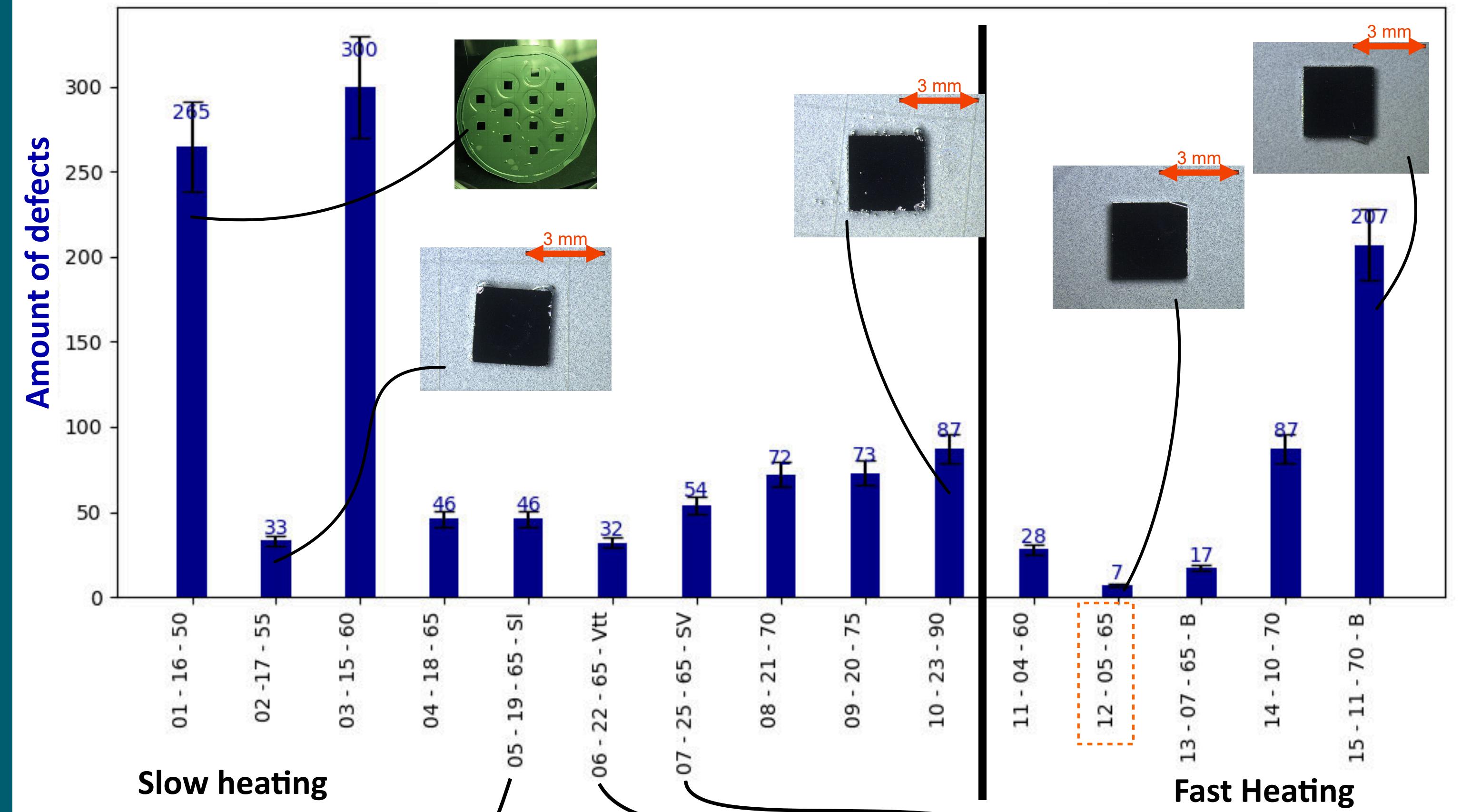
Characterisation of obtained samples



Lamination results

Comparison between several types of SUEX lamination: slow and fast heating cycles, with different lamination temperatures and an optional additional step

Comparison of total amount of defects per sample



Slow heating

05 - 19 - 65 - SI : variant 65°C

06 - 22 - 65 - Vtt : lamination 65°C

07 - 25 - 65 - SV : lamination 65°C

Long drying of sacrificial layer and chips step before lamination

Long vacuum step before lamination

Long vacuum and drying step of sacrificial layer and chips before lamination

3 mm

3 mm